

<b>Notice of References Cited</b>	Application/Control No. 10/018,584	Applicant(s)/Patent Under Reexamination RAITOLA, MIKA	
	Examiner Mark A. Mais	Art Unit 2616	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,697,635	02-2004	Bae, Eun Hae	455/522
*	B	US-6,804,531	10-2004	Komatsu, Masahiro	455/522
*	C	US-6,856,644	02-2005	Wang et al.	375/130
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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